SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

CONTECH RESEARCH INC.
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ELECTRICAL

Valid To: February 29, 2028 Certificate Number: 1478.02

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following tests on aerospace, aircraft, automotive, and computer components, cable assemblies, connectors, and interconnect systems, commercial and military:

Test:	**Test Method(s) [1]:**
Resistance Parameters ***(1 to 100) ma @ 20mv DC OC, 1 ma to 600 A DC***	
LLCR Manual, Semi-Automatic, and Automatic	EIA 364, TP 23; MIL-STD-1344, Method 3002[2]; MIL-DTL-55302; IEC 60512-2-1; USB 2.0, 3.0; SAE/USCAR-2; SAE/USCAR-30; SAE J2030
Contact Resistance	EIA 364, TP 06; MIL-STD-1344, Method 3004[2]; MIL-STD-202, Method 307; IEC 60512-2-2; SAE J2030
Voltage Drop	SAE/USCAR-2; SAE J2030
Shell-To-Shell and Shell-To-Bulkhead Resistance	EIA 364, TP 83; MIL-STD-1344, Method 3007[2]; IEC 60512-02-6
Rise Time Degradation	EIA 364, TP 102; MIL-PRF-49142 (par. 3.25 / 4.6.22)

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Test:	**Test Method(s) [1]:**
RF Hi Pot Withstanding Voltage	MIL-PRF-39012; MIL-PRF-49142 (par. 3.21 / 4.6.18)
Parameters *1 KHz to 1 GHz*	
Inductance	EIA 364, TP 33, TP 69
Capacitance	EIA 364, TP 30; MIL-STD-202, Method 305; IEC 60512-22-1; USB 2.0, 3.0
Detection Parameters ***1ns, 10 ns, 50ns, .1µs, 1 µs, 10µs***	
Low Nanosecond Event Detection	EIA 364, TP 87
Discontinuity Event Detection	EIA 364, TP 46; MIL-STD-202, Method 310; IEC 60512-2-5; SAE J2030
DWV Parameters ***(100 V - 6,000 VAC, 10 mbars)***	
DWV Sea Level	EIA3 64, TP 20; MIL-STD-1344, Method 3001[2]; MIL-STD-202, Method 301; UL 1977; IEC 60512-4-1; USB 2.0, 3.0
DWV Altitude	EIA 364, TP 20; IEC 60512-4-1
IR Parameters ***(100 to 6,000) V DC, 50,000 MΩ Max***	
Insulation Resistance	EIA 364, TP 21; MIL-STD-1344, Method 3003[2]; MIL-STD-202, Method 302; IEC 60512-3-1; USB 2.0, 3.0; SAE/USCAR-2; SAE/USCAR-30; SAE J2030

Test:	**Test Method(s) [1]:**
Parameters *100 mA to 600A DC*	
Current Cycling	EIA 364, TP 55; IEC 60512-9-5; SAE/USCAR-2; SAE J2030
Temperature Rise	EIA 364, TP 70; UL1977; IEC 60512-5-1; SAE/USCAR-2; SAE J2030
Mechanical Operations with Electrical Load	IEC 60512-9-3
Magnetic Permeability	EIA-364-TP-54; MIL-STD-1344, Method 3006[2]

[1] When the date, edition, version, etc. is not identified in the scope of accreditation, laboratories may use the version that immediately precedes the current version for a period of one year from the date of publication of the standard test method, per Annex A, Part C of A2LA's *R101 - General Requirements: Accreditation of Conformity Assessment Bodies.*

[2] This laboratory's scope contains withdrawn or superseded methods. As a clarifier, this indicates that the applicable method itself has been withdrawn or is now considered "historical" and not that the laboratory's accreditation for the method has been withdrawn.

Accredited Laboratory

A2LA has accredited

CONTECH RESEARCH INC.

Rumford, RI

for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated April 2017*).

Presented this 6th day of April 2026.

Mr. Trace McInturff, Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 1478.02
Valid to February 29, 2028

For the types of tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.